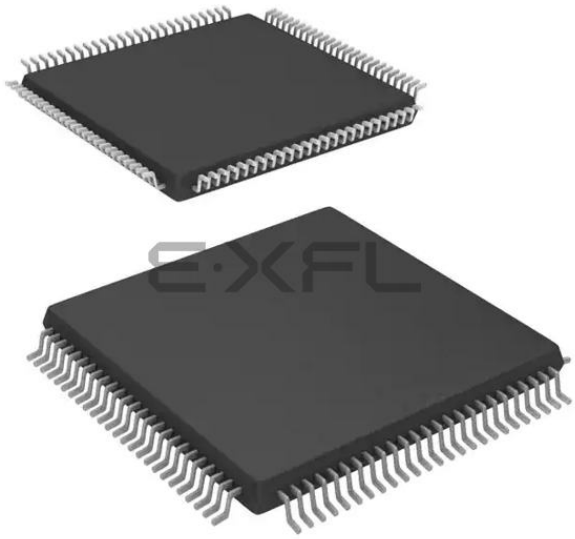

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	42
Number of Logic Elements/Cells	336
Total RAM Bits	-
Number of I/O	68
Number of Gates	4000
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epf8452atc100-4

JTAG BST circuitry	Yes	No	Yes	Yes	No	Yes

...and More Features

- Peripheral register for fast setup and clock-to-output delay
- Fabricated on an advanced SRAM process
- Available in a variety of packages with 84 to 304 pins (see Table 2)
- Software design support and automatic place-and-route provided by the Altera® MAX+PLUS® II development system for Windows-based PCs, as well as Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations
- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and Veribest

Table 2. FLEX 8000 Package Options & I/O Pin Count *Note (1)*

Device	84-Pin PLCC	100-Pin TQFP	144-Pin TQFP	160-Pin PQFP	160-Pin PGA	192-Pin PGA	208-Pin PQFP	225-Pin BGA	232-Pin PGA	240-Pin PQFP	280-Pin PGA	304-Pin RQFP
EPF8282A	68	78										
EPF8282AV		78										
EPF8452A	68	68		120	120							
EPF8636A	68			118		136	136					
EPF8820A			112	120		152	152	152				
EPF81188A							148		184	184		
EPF81500A										181	208	208

Note:
(1) FLEX 8000 device package types include plastic J-lead chip carrier (PLCC), thin quad flat pack (TQFP), plastic quad flat pack (PQFP), power quad flat pack (RQFP), ball-grid array (BGA), and pin-grid array (PGA) packages.

General Description

Altera's Flexible Logic Element MatriX (FLEX®) family combines the benefits of both erasable programmable logic devices (EPLDs) and field-programmable gate arrays (FPGAs). The FLEX 8000 device family is ideal for a variety of applications because it combines the fine-grained architecture and high register count characteristics of FPGAs with the high speed and predictable interconnect delays of EPLDs. Logic is implemented in LEs that include compact 4-input look-up tables (LUTs) and programmable registers. High performance is provided by a fast, continuous network of routing resources.

FLEX 8000 devices provide a large number of storage elements for applications such as digital signal processing (DSP), wide-data-path manipulation, and data transformation. These devices are an excellent choice for bus interfaces, TTL integration, coprocessor functions, and high-speed controllers. The high-pin-count packages can integrate multiple 32-bit buses into a single device. Table 3 shows FLEX 8000 performance and LE requirements for typical applications.

Table 3. FLEX 8000 Performance

Application	LEs Used	Speed Grade			Units
		A-2	A-3	A-4	
16-bit loadable counter	16	125	95	83	MHz
16-bit up/down counter	16	125	95	83	MHz
24-bit accumulator	24	87	67	58	MHz
16-bit address decode	4	4.2	4.9	6.3	ns
16-to-1 multiplexer	10	6.6	7.9	9.5	ns

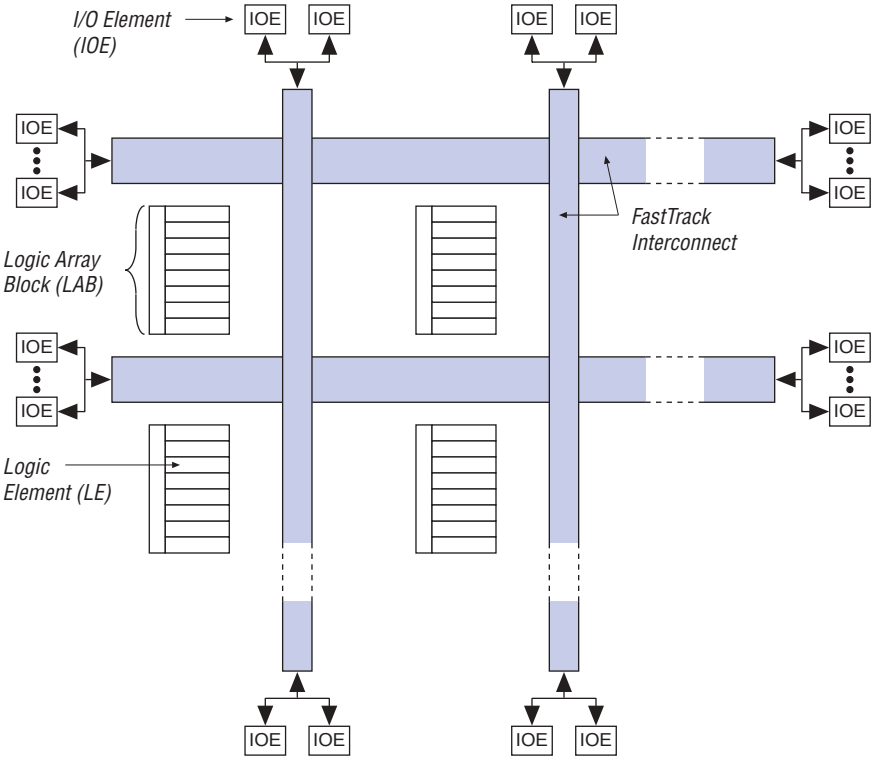
All FLEX 8000 device packages provide four dedicated inputs for synchronous control signals with large fan-outs. Each I/O pin has an associated register on the periphery of the device. As outputs, these registers provide fast clock-to-output times; as inputs, they offer quick setup times.

The logic and interconnections in the FLEX 8000 architecture are configured with CMOS SRAM elements. FLEX 8000 devices are configured at system power-up with data stored in an industry-standard parallel EPROM or an Altera serial configuration devices, or with data provided by a system controller. Altera offers the EPC1, EPC1213, EPC1064, and EPC1441 configuration devices, which configure FLEX 8000 devices via a serial data stream. Configuration data can also be stored in an industry-standard 32 K × 8 bit or larger configuration device, or downloaded from system RAM. After a FLEX 8000 device has been configured, it can be reconfigured in-circuit by resetting the device and loading new data. Because reconfiguration requires less than 100 ms, real-time changes can be made during system operation. For information on how to configure FLEX 8000 devices, go to the following documents:

- *Configuration Devices for APEX & FLEX Devices Data Sheet*
- *BitBlaster Serial Download Cable Data Sheet*
- *ByteBlasterMV Parallel Port Download Cable Data Sheet*
- *Application Note 33 (Configuring FLEX 8000 Devices)*
- *Application Note 38 (Configuring Multiple FLEX 8000 Devices)*

Figure 1 shows a block diagram of the FLEX 8000 architecture. Each group of eight LEs is combined into an LAB; LABs are arranged into rows and columns. The I/O pins are supported by I/O elements (IOEs) located at the ends of rows and columns. Each IOE contains a bidirectional I/O buffer and a flipflop that can be used as either an input or output register.

Figure 1. FLEX 8000 Device Block Diagram

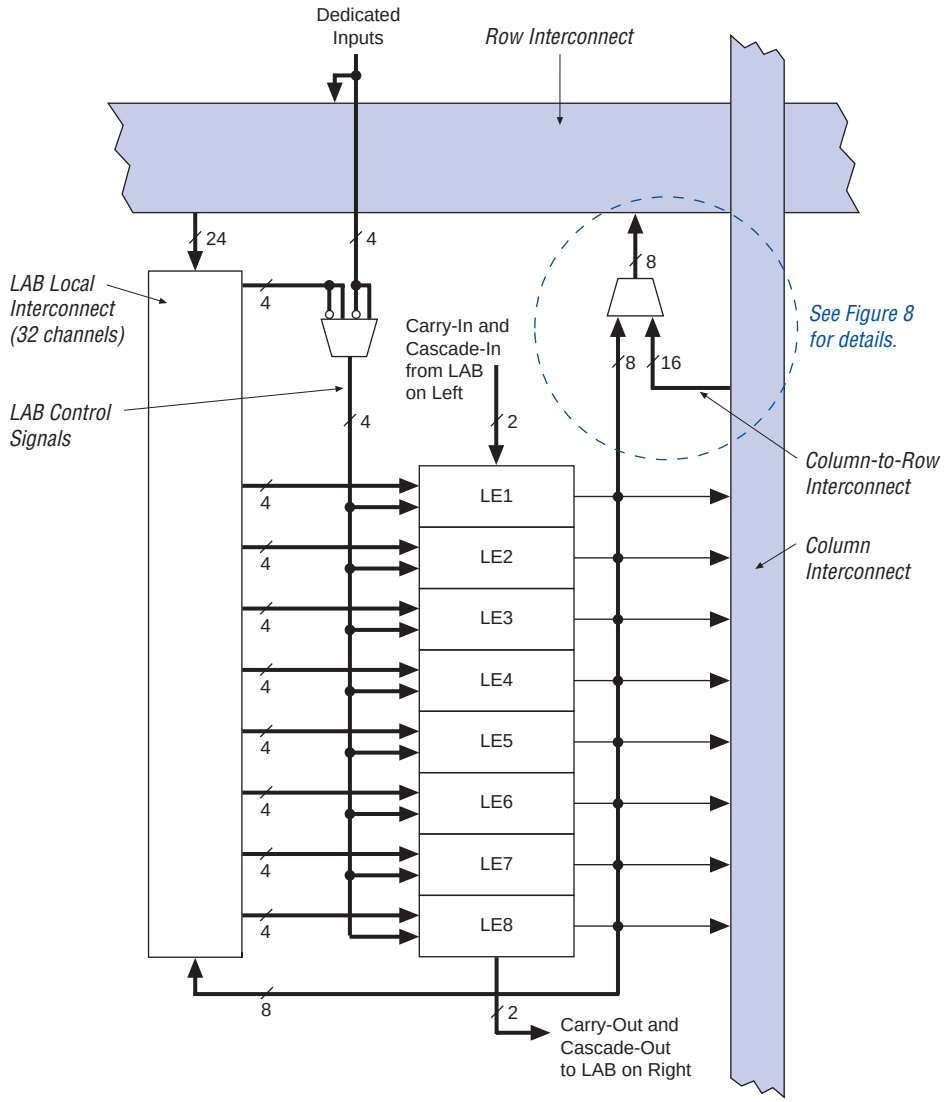


Signal interconnections within FLEX 8000 devices and between device pins are provided by the FastTrack Interconnect, a series of fast, continuous channels that run the entire length and width of the device. IOEs are located at the end of each row (horizontal) and column (vertical) FastTrack Interconnect path.

Logic Array Block

A logic array block (LAB) consists of eight LEs, their associated carry and cascade chains, LAB control signals, and the LAB local interconnect. The LAB provides the coarse-grained structure of the FLEX 8000 architecture. This structure enables FLEX 8000 devices to provide efficient routing, high device utilization, and high performance. Figure 2 shows a block diagram of the FLEX 8000 LAB.

Figure 2. FLEX 8000 Logic Array Block



Normal Mode

The normal mode is suitable for general logic applications and wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in signal are the inputs to a 4-input LUT. Using a configurable SRAM bit, the MAX+PLUS II Compiler automatically selects the carry-in or the DATA3 signal as an input. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. The LE-Out signal—the data output of the LE—is either the combinatorial output of the LUT and cascade chain, or the data output (Q) of the programmable register.

Arithmetic Mode

The arithmetic mode offers two 3-input LUTs that are ideal for implementing adders, accumulators, and comparators. One LUT provides a 3-bit function; the other generates a carry bit. As shown in Figure 6, the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, in an adder, this output is the sum of three bits: a, b, and the carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports a cascade chain.

Up/Down Counter Mode

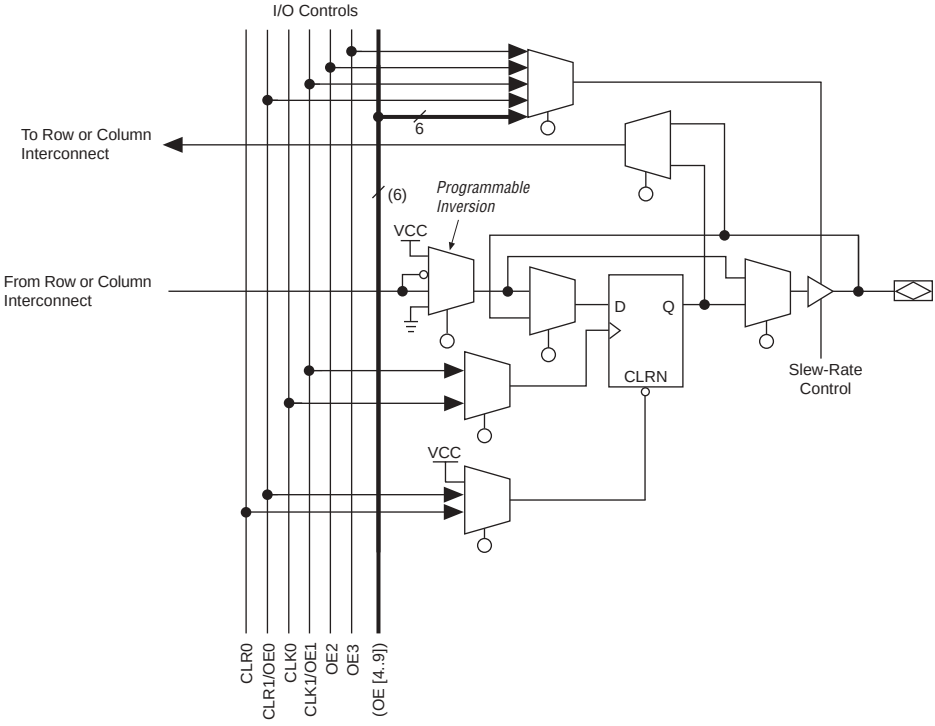
The up/down counter mode offers counter enable, synchronous up/down control, and data loading options. These control signals are generated by the data inputs from the LAB local interconnect, the carry-in signal, and output feedback from the programmable register. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. A 2-to-1 multiplexer provides synchronous loading. Data can also be loaded asynchronously with the clear and preset register control signals, without using the LUT resources.

Clearable Counter Mode

The clearable counter mode is similar to the up/down counter mode, but supports a synchronous clear instead of the up/down control; the clear function is substituted for the cascade-in signal in the up/down counter mode. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. Synchronous loading is provided by a 2-to-1 multiplexer, and the output of this multiplexer is ANDed with a synchronous clear.

Figure 10. FLEX 8000 IOE

Numbers in parentheses are for EPF81500A devices only.



Row-to-IOE Connections

Figure 11 illustrates the connection between row interconnect channels and IOEs. An input signal from an IOE can drive two separate row channels. When an IOE is used as an output, the signal is driven by an *n*-to-1 multiplexer that selects the row channels. The size of the multiplexer varies with the number of columns in a device. EPF81500A devices use a 27-to-1 multiplexer; EPF81188A, EPF8820A, EPF8636A, and EPF8452A devices use a 21-to-1 multiplexer; and EPF8282A and EPF8282AV devices use a 13-to-1 multiplexer. Eight IOEs are connected to each side of the row channels.

Table 5 lists the source of the peripheral control signal for each FLEX 8000 device by row.

Table 5. Row Sources of FLEX 8000 Peripheral Control Signals

Peripheral Control Signal	EPF8282A EPF8282AV	EPF8452A	EPF8636A	EPF8820A	EPF81188A	EPF81500A
CLK0	Row A	Row A	Row A	Row A	Row E	Row E
CLK1/OE1	Row B	Row B	Row C	Row C	Row B	Row B
CLR0	Row A	Row A	Row B	Row B	Row F	Row F
CLR1/OE0	Row B	Row B	Row C	Row D	Row C	Row C
OE2	Row A	Row A	Row A	Row A	Row D	Row A
OE3	Row B	Row B	Row B	Row B	Row A	Row A
OE4	–	–	–	–	–	Row B
OE5	–	–	–	–	–	Row C
OE6	–	–	–	–	–	Row D
OE7	–	–	–	–	–	Row D
OE8	–	–	–	–	–	Row E
OE9	–	–	–	–	–	Row F

Output Configuration

This section discusses slew-rate control and MultiVolt I/O interface operation for FLEX 8000 devices.

Slew-Rate Control

The output buffer in each IOE has an adjustable output slew rate that can be configured for low-noise or high-speed performance. A slow slew rate reduces system noise by slowing signal transitions, adding a maximum delay of 3.5 ns. The slow slew-rate setting affects only the falling edge of a signal. The fast slew rate should be used for speed-critical outputs in systems that are adequately protected against noise. Designers can specify the slew rate on a pin-by-pin basis during design entry or assign a default slew rate to all pins on a global basis.

For more information on high-speed system design, go to *Application Note 75 (High-Speed Board Designs)*.

Table 8. JTAG Timing Parameters & Values

Symbol	Parameter	EPF8282A EPF8282AV EPF8636A EPF8820A EPF81500A		Unit
		Min	Max	
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high-impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high-impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		35	ns
t_{JSZX}	Update register high-impedance to valid output		35	ns
t_{JSXZ}	Update register valid output to high-impedance		35	ns

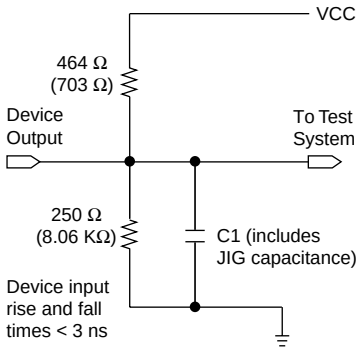
For detailed information on JTAG operation in FLEX 8000 devices, refer to *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)*.

Generic Testing

Each FLEX 8000 device is functionally tested and specified by Altera. Complete testing of each configurable SRAM bit and all logic functionality ensures 100% configuration yield. AC test measurements for FLEX 8000 devices are made under conditions equivalent to those shown in Figure 15. Designers can use multiple test patterns to configure devices during all stages of the production flow.

Figure 15. FLEX 8000 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in parentheses are for 3.3-V devices or outputs. Numbers without parentheses are for 5.0-V devices or outputs.



Operating Conditions

Tables 9 through 12 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for 5.0-V FLEX 8000 devices.

Table 9. FLEX 8000 5.0-V Device Absolute Maximum Ratings *Note (1)*

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	Supply voltage	With respect to ground *(2)*	–2.0	7.0	V
V_I	DC input voltage		–2.0	7.0	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	° C
T_{AMB}	Ambient temperature	Under bias	–65	135	° C
T_J	Junction temperature	Ceramic packages, under bias		150	° C
		PQFP and RQFP, under bias		135	° C

Table 17. FLEX 8000 Internal Timing Parameters *Note (1)*	
Symbol	**Parameter**
t_{IOD}	IOE register data delay
t_{IOC}	IOE register control signal delay
t_{IOE}	Output enable delay
t_{IOCO}	IOE register clock-to-output delay
t_{IOCOMB}	IOE combinatorial delay
t_{IOSU}	IOE register setup time before clock; IOE register recovery time after asynchronous clear
t_{IOH}	IOE register hold time after clock
t_{IOCLR}	IOE register clear delay
t_{IN}	Input pad and buffer delay
t_{OD1}	Output buffer and pad delay, slow slew rate = off, V_{CCIO} = 5.0 V C1 = 35 pF *(2)*
t_{OD2}	Output buffer and pad delay, slow slew rate = off, V_{CCIO} = 3.3 V C1 = 35 pF *(2)*
t_{OD3}	Output buffer and pad delay, slow slew rate = on, C1 = 35 pF *(3)*
t_{XZ}	Output buffer disable delay, C1 = 5 pF
t_{ZX1}	Output buffer enable delay, slow slew rate = off, V_{CCIO} = 5.0 V, C1 = 35 pF *(2)*
t_{ZX2}	Output buffer enable delay, slow slew rate = off, V_{CCIO} = 3.3 V, C1 = 35 pF *(2)*
t_{ZX3}	Output buffer enable delay, slow slew rate = on, C1 = 35 pF *(3)*

Table 18. FLEX 8000 LE Timing Parameters *Note (1)*	
Symbol	**Parameter**
t_{LUT}	LUT delay for data-in
t_{CLUT}	LUT delay for carry-in
t_{RLUT}	LUT delay for LE register feedback
t_{GATE}	Cascade gate delay
t_{CASC}	Cascade chain routing delay
t_{CICO}	Carry-in to carry-out delay
t_{CGEN}	Data-in to carry-out delay
t_{CGENR}	LE register feedback to carry-out delay
t_{C}	LE register control signal delay
t_{CH}	LE register clock high time
t_{CL}	LE register clock low time
t_{CO}	LE register clock-to-output delay
t_{COMB}	Combinatorial delay
t_{SU}	LE register setup time before clock; LE register recovery time after asynchronous preset, clear, or load
t_{H}	LE register hold time after clock
t_{PRE}	LE register preset delay
t_{CLR}	LE register clear delay

Table 19. FLEX 8000 Interconnect Timing Parameters Note (1)	
Symbol	**Parameter**
$t_{LABCASC}$	Cascade delay between LEs in different LABs
$t_{LABCARRY}$	Carry delay between LEs in different LABs
t_{LOCAL}	LAB local interconnect delay
t_{ROW}	Row interconnect routing delay *(4)*
t_{COL}	Column interconnect routing delay
t_{DIN_C}	Dedicated input to LE control delay
t_{DIN_D}	Dedicated input to LE data delay *(4)*
t_{DIN_IO}	Dedicated input to IOE control delay

Table 20. FLEX 8000 External Reference Timing Characteristics Note (5)	
Symbol	**Parameter**
t_{DRR}	Register-to-register delay via 4 LEs, 3 row interconnects, and 4 local interconnects *(6)*
t_{ODH}	Output data hold time after clock *(7)*

Notes to tables:

(1) Internal timing parameters cannot be measured explicitly. They are worst-case delays based on testable and external parameters specified by Altera. Internal timing parameters should be used for estimating device performance. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
(2) These values are specified in Table 10 on page 28 or Table 14 on page 29.
(3) For the t_{OD3} and t_{ZX3} parameters, V_{CCIO} = 3.3 V or 5.0 V.
(4) The t_{ROW} and t_{DIN_D} delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
(5) External reference timing characteristics are factory-tested, worst-case values specified by Altera. A representative subset of signal paths is tested to approximate typical device applications.
(6) For more information on test conditions, see *Application Note 76 (Understanding FLEX 8000 Timing)*.
(7) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies to global and non-global clocking, and for LE and I/O element registers.

The FLEX 8000 timing model shows the delays for various paths and functions in the circuit. See Figure 19. This model contains three distinct parts: the LE; the IOE; and the interconnect, including the row and column FastTrack Interconnect, LAB local interconnect, and carry and cascade interconnect paths. Each parameter shown in Figure 19 is expressed as a worst-case value in Tables 22 through 49. Hand-calculations that use the FLEX 8000 timing model and these timing parameters can be used to estimate FLEX 8000 device performance. Timing simulation or timing analysis after compilation is required to determine the final worst-case performance. Table 21 summarizes the interconnect paths shown in Figure 19.

For more information on timing parameters, go to *Application Note 76 (Understanding FLEX 8000 Timing)*.

Table 21. FLEX 8000 Timing Model Interconnect Paths

Source	Destination	Total Delay
LE-Out	LE in same LAB	t_{LOCAL}
LE-Out	LE in same row, different LAB	$t_{ROW} + t_{LOCAL}$
LE-Out	LE in different row	$t_{COL} + t_{ROW} + t_{LOCAL}$
LE-Out	IOE on column	t_{COL}
LE-Out	IOE on row	t_{ROW}
IOE on row	LE in same row	$t_{ROW} + t_{LOCAL}$
IOE on column	Any LE	$t_{COL} + t_{ROW} + t_{LOCAL}$

Tables 22 through 49 show the FLEX 8000 internal and external timing parameters.

Table 22. EPF8282A Internal I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		–		–		–	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		–		–		–	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 26. EPF8282AV I/O Element Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
t_{IOD}		0.9		2.2	ns
t_{IOC}		1.9		2.0	ns
t_{IOE}		1.9		2.0	ns
t_{IOCO}		1.0		2.0	ns
t_{IOCOMB}		0.1		0.0	ns
t_{IOSU}	1.8		2.8		ns
t_{IOH}	0.0		0.2		ns
t_{IOCLR}		1.2		2.3	ns
t_{IN}		1.7		3.4	ns
t_{OD1}		1.7		4.1	ns
t_{OD2}		–		–	ns
t_{OD3}		5.2		7.1	ns
t_{XZ}		1.8		4.3	ns
t_{ZX1}		1.8		4.3	ns
t_{ZX2}		–		–	ns
t_{ZX3}		5.3		8.3	ns

Table 27. EPF8282AV Interconnect Timing Parameters

Symbol	Speed Grade				Unit
	A-3		A-4		
	Min	Max	Min	Max	
$t_{LABCASC}$		0.4		1.3	ns
$t_{LABCARRY}$		0.4		0.8	ns
t_{LOCAL}		0.8		1.5	ns
t_{ROW}		4.2		6.3	ns
t_{COL}		2.5		3.8	ns
t_{DIN_C}		5.5		8.0	ns
t_{DIN_D}		7.2		10.8	ns
t_{DIN_IO}		5.5		9.0	ns

Table 30. EPF8452A I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		–		–		–	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		–		–		–	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 31. EPF8452A Interconnect Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.4		0.4	ns
$t_{LABCARRY}$		0.3		0.4		0.4	ns
t_{LOCAL}		0.5		0.5		0.7	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 46. EPF81500A I/O Element Timing Parameters

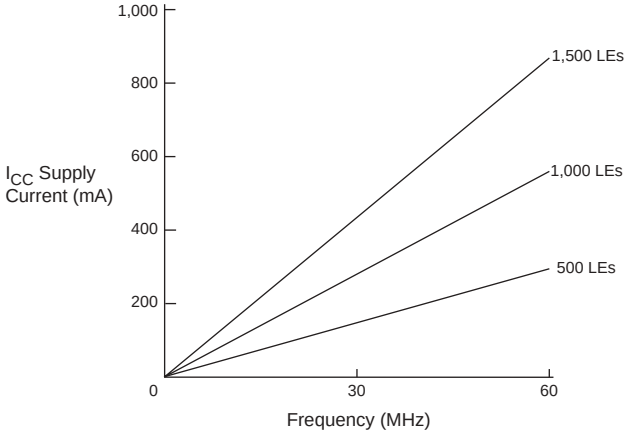
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		1.6		1.9		2.2	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		1.9		2.1		2.3	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 47. EPF81500A Interconnect Timing Parameters

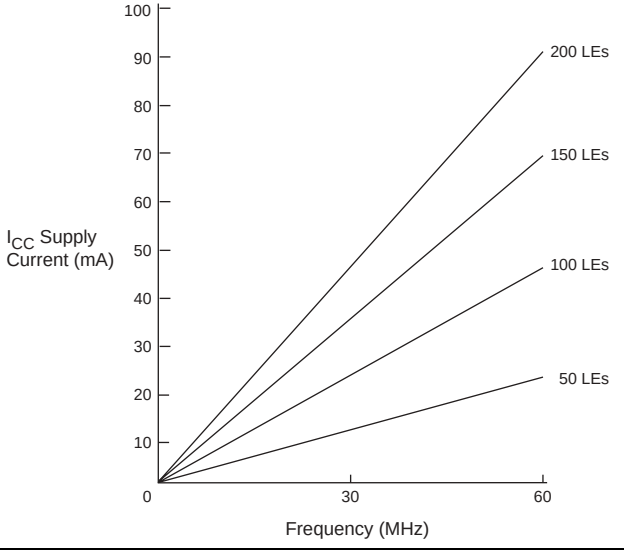
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.3		0.4	ns
$t_{LABCARRY}$		0.3		0.3		0.4	ns
t_{LOCAL}		0.5		0.6		0.8	ns
t_{ROW}		6.2		6.2		6.2	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		8.2		8.2		8.7	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Figure 20. FLEX 8000 $I_{CCACTIVE}$ vs. Operating Frequency

5.0-V FLEX 8000 Devices



3.3-V FLEX 8000 Devices



Configuration & Operation

The FLEX 8000 architecture supports several configuration schemes to load a design into the device(s) on the circuit board. This section summarizes the device operating modes and available device configuration schemes.

For more information, go to *Application Note 33 (Configuring FLEX 8000 Devices)* and *Application Note 38 (Configuring Multiple FLEX 8000 Devices)*.

Device Pin-Outs

Tables 52 through 54 show the pin names and numbers for the dedicated pins in each FLEX 8000 device package.

Table 52. FLEX 8000 84-, 100-, 144- & 160-Pin Package Pin-Outs (Part 1 of 3)

Pin Name	84-Pin PLCC EPF8282A	84-Pin PLCC EPF8452A EPF8636A	100-Pin TQFP EPF8282A EPF8282AV	100-Pin TQFP EPF8452A	144-Pin TQFP EPF8820A	160-Pin PGA EPF8452A	160-Pin PQFP EPF8820A *(1)*
nSP *(2)*	75	75	75	76	110	R1	1
MSEL0 *(2)*	74	74	74	75	109	P2	2
MSEL1 *(2)*	53	53	51	51	72	A1	44
nSTATUS *(2)*	32	32	24	25	37	C13	82
nCONFIG *(2)*	33	33	25	26	38	A15	81
DCLK *(2)*	10	10	100	100	143	P14	125
CONF_DONE *(2)*	11	11	1	1	144	N13	124
nWS	30	30	22	23	33	F13	87
nRS	48	48	42	45	31	C6	89
RDCLK	49	49	45	46	12	B5	110
nCS	29	29	21	22	4	D15	118
CS	28	28	19	21	3	E15	121
RDYnBUSY	77	77	77	78	20	P3	100
CLKUSR	50	50	47	47	13	C5	107
ADD17	51	51	49	48	75	B4	40
ADD16	36	55	28	54	76	E2	39
ADD15	56	56	55	55	77	D1	38
ADD14	57	57	57	57	78	E1	37
ADD13	58	58	58	58	79	F3	36
ADD12	60	60	59	60	83	F2	32
ADD11	61	61	60	61	85	F1	30
ADD10	62	62	61	62	87	G2	28
ADD9	63	63	62	64	89	G1	26
ADD8	64	64	64	65	92	H1	22
ADD7	65	65	65	66	94	H2	20
ADD6	66	66	66	67	95	J1	18
ADD5	67	67	67	68	97	J2	16
ADD4	69	69	68	70	102	K2	11
ADD3	70	70	69	71	103	K1	10
ADD2	71	71	71	72	104	K3	8
ADD1	76	72	76	73	105	M1	7

Table 52. FLEX 8000 84-, 100-, 144- & 160-Pin Package Pin-Outs (Part 2 of 3)

Pin Name	84-Pin PLCC EPF8282A	84-Pin PLCC EPF8452A EPF8636A	100-Pin TQFP EPF8282A EPF8282AV	100-Pin TQFP EPF8452A	144-Pin TQFP EPF8820A	160-Pin PGA EPF8452A	160-Pin PQFP EPF8820A *(1)*
ADD0	78	76	78	77	106	N3	6
DATA7	3	2	90	89	131	P8	140
DATA6	4	4	91	91	132	P10	139
DATA5	6	6	92	95	133	R12	138
DATA4	7	7	95	96	134	R13	136
DATA3	8	8	97	97	135	P13	135
DATA2	9	9	99	98	137	R14	133
DATA1	13	13	4	4	138	N15	132
DATA0	14	14	5	5	140	K13	129
SDOUT *(3)*	79	78	79	79	23	P4	97
TDI *(4)*	55	45 *(5)*	54	–	96	–	17
TDO *(4)*	27	27 *(5)*	18	–	18	–	102
TCK *(4)*, *(6)*	72	44 *(5)*	72	–	88	–	27
TMS *(4)*	20	43 *(5)*	11	–	86	–	29
TRST *(7)*	52	52 *(8)*	50	–	71	–	45
Dedicated Inputs *(10)*	12, 31, 54, 73	12, 31, 54, 73	3, 23, 53, 73	3, 24, 53, 74	9, 26, 82, 99	C3, D14, N2, R15	14, 33, 94, 113
VCCINT	17, 38, 59, 80	17, 38, 59, 80	6, 20, 37, 56, 70, 87	9, 32, 49, 59, 82	8, 28, 70, 90, 111	B2, C4, D3, D8, D12, G3, G12, H4, H13, J3, J12, M4, M7, M9, M13, N12	3, 24, 46, 92, 114, 160
VCCIO	–	–	–	–	16, 40, 60, 69, 91, 112, 122, 141	–	23, 47, 57, 69, 79, 104, 127, 137, 149, 159

Table 52. FLEX 8000 84-, 100-, 144- & 160-Pin Package Pin-Outs (Part 3 of 3)

Pin Name	84-Pin PLCC EPF8282A	84-Pin PLCC EPF8452A EPF8636A	100-Pin TQFP EPF8282A EPF8282AV	100-Pin TQFP EPF8452A	144-Pin TQFP EPF8820A	160-Pin PGA EPF8452A	160-Pin PQFP EPF8820A *(1)*
GND	5, 26, 47, 68	5, 26, 47, 68	2, 13, 30, 44, 52, 63, 80, 94	19, 44, 69, 94	7, 17, 27, 39, 54, 80, 81, 100,101, 128, 142	C12, D4, D7, D9, D13, G4, G13, H3, H12, J4, J13, L1, M3, M8, M12, M15, N4	12, 13, 34, 35, 51, 63, 75, 80, 83, 93, 103, 115, 126, 131, 143, 155
No Connect (N.C.)	–	–	–	2, 6, 13, 30, 37, 42, 43, 50, 52, 56, 63, 80, 87, 92, 93, 99	–	–	–
Total User I/O Pins *(9)*	64	64	74	64	108	116	116

Table 54. FLEX 8000 225-, 232-, 240-, 280- & 304-Pin Package Pin-Outs (Part 3 of 3)

Pin Name	225-Pin BGA EPF8820A	232-Pin PGA EPF81188A	240-Pin PQFP EPF81188A	240-Pin PQFP EPF81500A	280-Pin PGA EPF81500A	304-Pin RQFP EPF81500A
GND	B1, D4, E14, F7, F8, F9, F12, G6, G7, G8, G9, G10, H1, H4, H5, H6, H7, H8, H9, H10, H11, J6, J7, J8, J9, J10, K6, K7, K8, K9, K11, L15, N3, P1	A1, D6, E11, E7, E9, G4, G5, G13, G14, J5, J13, K4, K14, L5, L13, N4, N7, N9, N11, N14	8, 9, 30, 31, 52, 53, 72, 90, 108, 115, 129, 139, 151, 161, 173, 185, 187, 193, 211, 229	6, 7, 28, 29, 50, 51, 71, 85, 92, 101, 118, 119, 140, 141, 162, 163, 184, 185, 186, 198, 208, 214, 228	D4, D5, D16, E4, E5, E6, E15, E16, F5, F15, G5, G15, H5, H15, J5, J15, K5, K15, L5, L15, M5, M15, N5, N15, P4, P5, P15, P16, R4, R5, R15, R16, T4, T5, T16, U17	9, 11, 36, 38, 65, 67, 90, 108, 116, 128, 150, 151, 175, 177, 206, 208, 231, 232, 237, 253, 265, 273, 291
No Connect (N.C.)	–	–	61, 62, 119, 120, 181, 182, 239, 240	–	–	10, 21, 23, 25, 35, 37, 39, 40, 41, 42, 52, 55, 66, 68, 146, 147, 161, 173, 174, 176, 187, 188, 189, 190, 192, 194, 195, 205, 207, 219, 221, 233, 234, 235, 236, 302, 303
Total User I/O Pins *(9)*	148	180	180	177	204	204